



COURSE OVERVIEW FE0772-10D Phased Array Ultrasonic Testing Level II Training & Certification (ASNT, SNT-TC-1A)

Course Title

Phased Array Ultrasonic Testing Level II Training & Certification (ASNT, SNT-TC-1A)

Course Date/Venue

Session 1: April 06-17, 2025/Boardroom 1, Elite Byblos Hotel Al Barsha, Sheikh Zaved Road, Dubai, UAE

Session 2: September 28-October 09, 2025/Boardroom 1, Elite Byblos Hotel Al Barsha, Sheikh Zayed Road, Dubai, UAE O CEUS



Course Reference FE0772-10D

Course Duration/Credits

Ten days (80 hours)/8.0CEUs/80 PDHs

Course Description







This practical and highly-interactive course includes various practical sessions and exercises. Theorv learnt will be applied using our state-of-the-art simulators.

This course will provide participants the theory lectures and practical training with a preliminary understanding of Phase Array Ultrasonic Testing as per the ANSI/ASNT CP-105-2016 Standard for qualification of nondestructive testing personnel and as per the ASNT Recommended Practice No. SNT-TC-1A 2016 for Personnel Qualification and Certification in Nondestructive Testing.

Sample Questions for general examinations will be presented in the question booklet C that was obtained from ASNT headquarters. Participants will further demonstrate familiarity with and ability to operate the necessary equipment for Phased Array Ultrasonic Testing, record and analyse the resultant information to the degree required as well as test flawed specimen and component and analyse the results of NDT as part of the practical training.

At the completion of the course, participants will be appearing for a Level II exam. Each candidate will be a 'Certified ASNT NDT Level II in Phased Array Testing' upon successfully passing the examination with a minimum passing composite grade of at least 80 percent (%) which will be administered and graded by Haward Technology through its Certified ASNT Level-III instructors.



FE0772-10D - Page 1 of 15



FE0772-10D-04-25|Rev.40|08 November 2024





Course Objectives

Upon the successful completion of this course, each participant will be able to:-

- Get certified as a "Certified ASNT Level II in Phased Array Ultrasonic Testing"
- Discuss the terminologies of phase array, including its history and the levels of certification responsibilities
- Explain the basic principles of phase array, ultrasonic wave theory that include longitudinal and shear wave as well as phase array concepts and theory
- Identify the computer-based systems equipment, focal law generation, probes, wedges and scanners
- Carryout testing techniques thru linear, sectorial and electronic scans
- Employ proper calibration covering active element and probe checks, wedge delay, velocity, exit point verifications, refractions angle verifications, sensitivity, DAC, TCG, TVG and ACG variables and parameters
- Identify the effects of curvature and focusing the effects
- Apply data collection using single probes, multiple probes and multiple groups or multiplexing single/multiples probes
- Recognize non-encoded scans, encoded scans, zone discrimination, scan plans, exam coverages and probe offsets and indexing
- Carryout various procedures for specific applications, data presentations, data evaluation and reporting

Exclusive Smart Training Kit - H-STK[®]



Participants of this course will receive the exclusive "Haward Smart Training Kit" (H-STK®). The H-STK® consists of a comprehensive set of technical content which includes electronic version of the course materials conveniently saved in a **Tablet PC**.

Who Should Attend

This course provides an overview of all significant aspects and considerations of ultrasonic testing in accordance with the ASNT international standard for all engineers and other technical staff working in the field of welding technology and quality assurance of welded joints using ultrasonic testing and in order to investigate material with such technique.

Course Prerequisite Criteria

	Initial Training & Experience Levels			
	Level	Training Hours	Minimum Hours in Method	Total Hours in NDT
	Ultrasonic Level II	80	160	N/A
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Examinations Category & Criteria

Vision Examinations

- Near-Vision Acuity
 - This examination will ensure natural or corrected near-distance acuity in at least one eye such that the applicant is capable of reading a minimum of Jaeger Number 2 or equivalent type and size letter at the distance designated on the chart but not less than12 inches (30.5 cm) or a standard Jaeger test chart. The ability to perceive an Ortho-Rater minimum of 8 or similar test pattern is also acceptable. This examination shall be administered annually.
- Color Contrast Differentiation
 - This examination will demonstrate the capability of distinguishing and differentiating contrast among colors or shades of gray used in the applicable NDT method. This shall be conducted upon initial certification and at five-year intervals thereafter.

Specific (Written)

- This examination will address the equipment, operating procedures and NDT techniques that the individual may encounter during specific assignments to the degree required by the employer's written practice
- The specific examination will also cover the specifications or codes and acceptance criteria used in the employer's NDT procedures
- The minimum number of examination questions that will be given is 30

Practical

- The candidate shall demonstrate familiarity with and ability to operate the necessary NDT equipment, record and analyse the resultant information to the degree required
- At least one flawed specimen or component shall be tested and the results of the NDT analysed by the candidate
- The description of the specimen, the NDT procedure including check points and the results of the examination shall be documented
- Proficiency shall be demonstrated in performing the Ultrasonic Testing on one or more specimens or machine problems approved by the NDT Level III and in evaluating the results to the degree of responsibility as described in the employer's written practice. At least ten (10) different checkpoints requiring an understanding of test variables and the employer's procedural requirements will be included. The candidate shall detect all discontinuities and conditions specified by the NDT Level III

Note: While it is normal to score the practical on a percentile basis, practical examinations will contain check points that failure to successfully complete will result in failure of the examination

Additional Criteria

All written examinations will be closed-book except that necessary data such as graphs, tables, specifications, procedures, codes, etc., may be provided during the examination. All questions are approved by the responsible NDT Level III.



FE0772-10D - Page 3 of 15







Course Certificate(s)

(1) Internationally recognized Qualification Certificates will be issued to participants who have successfully completed the course and passed the exam at the end of the course. Successful candidate will be certified as a "Certified ASNT Level II in Phased Array Ultrasonic Testing". Qualification Certificate is valid for 5 years.

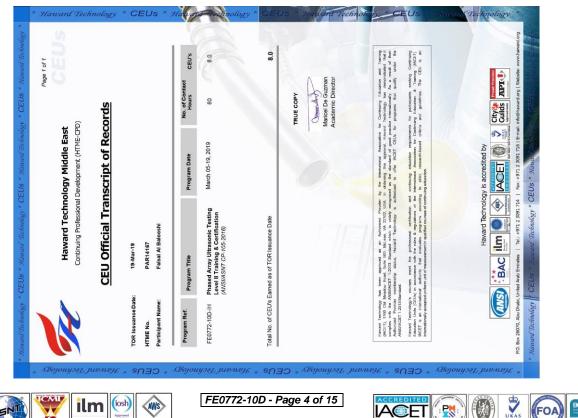
Qualification Certificate(s)

BAC

The following qualification certificate is a sample of the qualification certificates that will be issued to successful candidates:



(2) Official Transcript of Records will be provided to the successful delegates with the equivalent number of ANSI/IACET Accredited Continuing Education Units (CEUs) earned during the course.



FE0772-10D-04-25|Rev.40|08 November 2024





Certificate Accreditations

Haward Technology is accredited by the following international accreditation organizations: -

The American Society for Nondestructive Testing (ASNT)

Haward Technology's instructors are certified by The American Society for Nondestructive Testing (ASNT) and are authorized to conduct ASNT's certification programs for specific NDT methods in accordance with ASNT-TC-1A (2016). ASNT is the world's largest technical society for nondestructive testing (NDT) that provides a forum for exchange of NDT technical information, NDT educational materials and programs, and standards and services for the qualification and certification of NDT personnel.

*** BAC

British Accreditation Council (BAC)

Haward Technology is accredited by the British Accreditation Council for Independent Further and Higher Education as an International Centre. BAC is the British accrediting body responsible for setting standards within independent further and higher education sector in the UK and overseas. As a BAC-accredited international centre, Haward Technology meets all of the international higher education criteria and standards set by BAC.

USA International Association for Continuing Education and Training ACET (IACET)

Haward Technology is an Authorized Training Provider by the International Association for Continuing Education and Training (IACET), 2201 Cooperative Way, Suite 600, Herndon, Virginia 20171, USA. In obtaining this authority, Haward Technology has demonstrated that it complies with the ANSI/IACET 2018-1 Standard which is widely recognized as the standard of good practice internationally. As a result of our Authorized Provider membership status, Haward Technology is authorized to offer IACET CEUs for its programs that qualify under the ANSI/IACET 2018-1 Standard.

Haward Technology's courses meet the professional certification and continuing education requirements for participants seeking Continuing Education Units (CEUs) in accordance with the rules & regulations of the International Association for Continuing Education & Training (IACET). IACET is an international authority that evaluates programs according to strict, researchbased criteria and guidelines. The CEU is an internationally accepted uniform unit of measurement in gualified courses of continuing education.

Haward Technology Middle East will award 8.0 CEUs (Continuing Education Units) or 80 PDHs (Professional Development Hours) for participants who completed the total tuition hours of this program. One CEU is equivalent to ten Professional Development Hours (PDHs) or ten contact hours of the participation in and completion of Haward Technology programs. A permanent record of a participant's involvement and awarding of CEU will be maintained by Haward Technology. Haward Technology will provide a copy of the participant's CEU and PDH Transcript of Records upon request.



FE0772-10D - Page 5 of 15







Course Instructor(s)

This course will be conducted by the following instructor(s). However, we have the right to change the course instructor(s) prior to the course date and inform participants accordingly:



Mr. Luis Lopez is a Senior Inspection Engineer with extensive experience within the Oil & Gas, Petrochemical and Refinery industries. His expertise widely covers in the areas of Thermography, Thermal Infrared Testing, Radiographic Film Interpretation, Visual Testing, Phased Array Ultrasonic Testing, Ultrasonic Testing, Magnetic Particle Testing, Liquid Penetrant Testing, Non-destructive Testing, NDT Methods & Applications, Electromagnetic Testing, Hydrostatic Leak Testing, Eddy Current

Testing, Valve Inspection & Testing, Codes & Standards Interpretation, Corrosion Engineering, Corrosion & Metallurgy, Welding & Corrosion Engineering, Welding Metrology, International Welding Codes, Practical Welding Technology, Plastic Pipe Welding, Welding Inspection, Welding Defects Analysis, Welding Joints & Coating Inspection, Post Weld Heat Treatment, Hardness Testing, Welding Electrodes Monitoring & Control, Pipe Testing, Piping System, Steel Structures, Metals Casting, Crane Functional Testing & Load Testing, Hydrotesting, Pressure Testing Procedure, Pressure Equipment Calibration, Stream Inspection, Corrosion Evaluation, Casting Products Inspection and Raw Materials Inspection. He is currently the Senior NDT Instructor of SETE wherein he is deeply involved in thermography, NDT qualification and certification of personnel.

During his career life, Mr. Lopez gained his practical and field experience through his various significant positions and dedication as the **Technical Manager**, **NDT Instructor**, **NDT Manager & Instructor**, **NDT Inspector**, **NDT Offshore Inspector & Quality Control**, **Phased Array Ultrasonic Technician** and **Radiographic Testing Technician** for various international companies such as the JP Inspections, Nova Inspection, NSD Services, Cotemar, UNISPEC Inspection and Ruiver.

Mr. Lopez holds a Diploma in Professional Mechanical & Electrical Technician. Certified Instructor/Trainer, Further. he is а Certified Internal а Verifier/Assessor/Trainer by the Institute of Leadership and Management (ILM), a Certified ASNT-NDT Level III Inspector in Infrared & Thermal Testing (IR), Liquid Penetrant Testing (PT), Magnetic Particle Testing (MT), Ultrasonic Testing (UT), Visual Testing (VT), Radiography Testing (RT), Leak Testing (LT), Electromagnetic Testing (ET), Certified Welding Inspection & Metallurgy Professional (API 577) and a Certified AWS-CWI Welding Inspector. He has further delivered numerous trainings, courses, workshops, seminars and conferences internationally.

Course Fee

US\$ 12,000 per Delegate + **VAT**. This rate includes H-STK® (Haward Smart Training Kit), buffet lunch, coffee/tea on arrival, morning & afternoon of each day.

Accommodation

Accommodation is not included in the course fees. However, any accommodation required can be arranged at the time of booking.



FE0772-10D - Page 6 of 15 FE0772-10D-04-25/Rev.40/08 November 2024

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Course Program

The following program is planned for this course. However, the course instructor(s) may modify this program before or during the course for technical reasons with no prior notice to participants. Nevertheless, the course objectives will always be met:

Dav 1

Day	
0730 – 0800	Registration & Coffee
0800 - 0815	Welcome & Introduction
0815 - 0830	PRE-TEST
	Introduction
0830 - 0930	Terminology of PA (Phased Array) • History of PA - Medical Sound Etc. •
	Responsibilities of Levels of Certification
0930 - 0945	Break
0945 – 1200	Basic Principles of PA
0943 - 1200	Review of Ultrasonic Wave Theory: Longitudinal & Shear Wave
1200 – 1300	Lunch Break
1300 - 1500	Basic Principles of PA (cont'd)
1300 - 1300	Review of Ultrasonic Wave Theory: Longitudinal & Shear Wave
1500 – 1515	Break
1515 - 1650	Basic Principles of PA (cont'd)
1515 - 1650	Introduction to PA Concepts & Theory
1650 – 1700	Recap
1700	End of Day One

Dav 2

Day Z	
0730 – 0930	Equipment Computer-Based Systems (Processors, Control Panel Including Input & Output Sockets, Block Diagram Showing Basic Internal Circuit Modules) • Computer-Based Systems (Multi-Element/Multi-Channel Configurations, Portable Battery Operated Versus Full Computer-Based Systems)
0930 - 0945	Break
0945 – 1200	<i>Equipment (cont'd)</i> <i>Focal Law Generation (Onboard Focal Law Generator)</i> • <i>Focal Law</i> <i>Generation (External Focal Law Generator)</i>
1200 - 1300	Lunch Break
1300 – 1500	<i>Equipment (cont'd)</i> <i>Probes (Composite Materials, Pitch, Gap, & Size, Passive Planes, Active</i> <i>Planes)</i> • <i>Probes (Arrays: 1D, 2D, Polar, Annular, Special Shape, etc, Beam</i> & Wave Forming, Grating Lobes)
1500 - 1515	Break
1515 - 1650	<i>Equipment (cont'd)</i> Wedges (Types of Wedge Designs) • Scanners (Mechanized, Manual)
1650 - 1700	Recap
1700	End of Day Two



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Day 3

Duy 5	
0730 - 0930	Testing Techniques Linear Scans
0930 - 0945	Break
0945 - 1200	Testing Techniques (cont'd) Sectorial Scans
1200 - 1300	Lunch Break
1300 – 1500	Testing Techniques (cont'd) Electronic Scans
1500 - 1515	Break
1515 - 1650	Testing Techniques (cont'd) Electronic Scans
1650 - 1700	Recap
1700	End of Day Three

Dav 4

Day 4	
0730 - 0930	Calibration Active Element & Probe Checks
0930 - 0945	Break
0945 – 1200	Calibration (cont'd) Wedge Delay
1200 - 1300	Lunch Break
1300 – 1500	<i>Calibration (cont'd)</i> <i>Velocity</i> • <i>Exit Point Verifications</i>
1500 – 1515	Break
1515 – 1650	Calibration (cont'd) Refraction Angle Verifications
1650 – 1700	Recap
1700	End of Day Four

Dav 5

Buyo	
0730 - 0930	Calibration (cont'd)
0730 - 0930	Sensitivity
0930 - 0945	Break
0945 – 1200	Calibration (cont'd)
0945 - 1200	DAC, TCG, TVG & ACG Variables & Parameters
1200 – 1300	Lunch
1300 - 1500	Calibration (cont'd)
1500 - 1500	Effects of Curvature • Focusing Effects
1500 – 1515	Break
1515 - 1645	Calibration (cont'd)
1515 - 1045	Beam Steering • Acquisition Gates
1645 – 1700	Recap
1700	End of Day Five



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Day 6

0730 - 0930	Data Collection Single Probes • Multiple Probes • Multiple Groups or Multiplexing Single/Multiple Probes
0930 - 0945	Break
0945 – 1200	Data Collection (cont'd) Non-Encoded Scans (Time-Based Data Storage) • Encoded Scans (Line Scans, Raster Scans) • Zone Discrimination
1200 - 1300	Lunch Break
1300 – 1500	Data Collection (cont'd) Scan Plans & Exam Coverages (Sectorial, Linear, Electronic Raster Scans)
1500 - 1515	Break
1515 - 1650	Data Collection (cont'd) Probe Offsets & Indexing
1650 - 1700	Recap
1700	End of Day Six

Day 7

Day	
0730 - 0930	Procedures Specific Applications (Material Evaluations, Components Evaluation, Weld
	Inspections)
0930 - 0945	Break
0945 – 1200	Procedures (cont'd)
0945 - 1200	Data Presentations (Standard, Other)
1200 - 1300	Lunch Break
1300 - 1500	Procedures (cont'd)
1500 - 1500	Data Evaluation (Codes/Standards/Specifications)
1500 - 1515	Break
1515 - 1650	Procedures (cont'd)
1515 - 1650	Data Evaluation (Flaw Characterization)
1650 – 1700	Recap
1700	End of Day Seven

Dav 8

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0730 - 0930	Procedures (cont'd) Data Evaluation (Flaw Dimensioning, Geometry, Software Tools)
0930 - 0945	Break
0945 – 1200	Procedures (cont'd) Data Evaluation (Evaluation Gates)
1200 - 1300	Lunch Break
1300 - 1500	Procedures (cont'd) Reporting (Imaging Outputs)
1500 - 1515	Break
1515 - 1650	Procedures (cont'd) Reporting (Onboard Reporting Tools, Plotting, ACAD, Etc.)
1650 – 1700	Recap
1700	End of Day Eight



FE0772-10D - Page 9 of 15

AWS







Day 9

0730 - 0800 Specific Theory Examination (30 minutes) 0800 - 0900 Specific Practical Examination (60 minutes) (A) Assembly, & Functional Check of the MEPAUT Equipment, Including Probe/s & Encoder. Probe 'Element Check', to be Saved as 'Data File' & 'HTML Report' 0900 - 0915 Break Specific Practical Examination (2 hours per Sample) : Sample 1 (B) Production of Complete Data File from Three Samples Selected by the Examiner, Including Set Up & Preparation of the Specimen & Visual Examination, Scan Plans, Carrying Out Tests, Post Test Procedures, Collecting & Storing Test Data. The Candidate Shall Demonstrate Beam Steering, Encoding Parameters, Focusing & DAC/TCG Production &, In Adittion, Demonstrate Completeness of Data. Weld Preparation Should Include Double-V & Single-V Configurations, With Varying Wall Thicknesses. 1115 - 1215 Lunch Specific Practical Examination (2 hours per Sample) : Sample 2 (B) Production of Complete Data File from Three Samples Selected by the Examination, Scan Plans, Carrying Out Tests, Post Test Procedures, Collecting & Storing Test Data. The Candidate Shall Demonstrate Beam Steering, Encoding Parameters, Focusing & DAC/TCG Production &, In Adittion, Demonstrate Completeness of Data. Weld Preparation Should Include Double-V & Single-V Configurations, With Varying Wall Thicknesses. 1215 - 1415 Collecting & Storing Test Data. The Candidate Shall Demonstrate Beam Steering, Encoding Parameters, Focusing & DAC/TCG Production &, In Adittion, Demonstrate Completeness of Data. Weld Preparation Should Include Double-V & Single-V Configurations, With Varying Wall Thicknesses. 1430 - 1630 Spec	Duy 5	
0800 - 0900 (Å) Åssembly, & Functional Check of the MEPAUT Equipment, Including Probe/s & Encoder. Probe 'Element Check', to be Saved as 'Data File' & 'HTML Report' 0900 - 0915 Break Specific Practical Examination (2 hours per Sample) : Sample 1 (B) Production of Complete Data File from Three Samples Selected by the Examiner, Including Set Up & Preparation of the Specimen & Visual Examination, Scan Plans, Carrying Out Tests, Post Test Procedures, Collecting & Storing Test Data. The Candidate Shall Demonstrate Beam Steering, Encoding Parameters, Focusing & DAC/TCG Production &, In Adittion, Demonstrate Completeness of Data. Weld Preparation Should Include Double-V & Single-V Configurations, With Varying Wall Thicknesses. 1115 - 1215 Lunch Specific Practical Examination (2 hours per Sample) : Sample 2 (B) Production of Complete Data File from Three Samples Selected by the Examination, Scan Plans, Carrying Out Tests, Post Test Procedures, Collecting & Storing Test Data. The Candidate Shall Demonstrate Beam Steering, Encoding Parameters, Focusing & DAC/TCG Production &, In Adition, Demonstrate Completeness of Data. Weld Preparation Should Include Double-V & Single-V Configurations, With Varying Wall Thicknesses. 1215 - 1415 Specific Practical Examination (2 hours per Sample) : Sample 3 (B) Production of Complete Data File from Three Samples Selected by the Examination, Scan Plans, Carrying Out Tests, Post Test Procedures, Collecting & Storing Test Data. The Candidate Shall Demonstrate Beam Steering, Encoding Parameters, Focusing & DAC/TCG Production &, In Adition, Demonstrate Completeness of Data. Weld Preparation Should Include Double-V & Single-V Configurat	0730 - 0800	Specific Theory Examination (30 minutes)
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	1650 - 1700	Recap
1700 End of Day Nine	1700	End of Day Nine

Day 10

0730 - 0930	Specific Practical Examination (2 hours per Data File) : Data File 1 (C) Examination & Assessment & Analysis of the Three Date Files from the Above Samples, Using Appropriate Viewing Software. Candidates Shall Complete a Test Report with the Results in a Prescribed Format Which Indicates Defect Location & Size. The Report Shall Also Include Discontinuity Characterization (Size & Position of Defects in Relation to a Known Datum/s) & Evaluation, Echo Dynamic Characterization. The Report Shall Include Detection of Mandatory Discontinuities.
0930 - 0945	Break



FE0772-10D - Page 10 of 15

AWS

IACET UKAS FOA FE0772-10D-04-25|Rev.40|08 November 2024





	Specific Practical Examination (2 hours per Data File) : Data File 2
	(C) Examination & Assessment & Analysis of the Three Date Files from the
	Above Samples, Using Appropriate Viewing Software. Candidates Shall
0945 - 1145	Complete a Test Report with the Results in a Prescribed Format Which
0945 - 1145	Indicates Defect Location & Size. The Report Shall Also Include Discontinuity
	<i>Characterization (Size & Position of Defects in Relation to a Known Datum/s)</i>
	& Evaluation, Echo Dynamic Characterization. The Report Shall Include
	Detection of Mandatory Discontinuities.
1145 - 1215	Lunch
	Specific Practical Examination (2 hours per Data File) : Data File 3
	(C) Examination & Assessment & Analysis of the Three Date Files from the
	Above Samples, Using Appropriate Viewing Software. Candidates Shall
1015 1415	Complete a Test Report with the Results in a Prescribed Format Which
1215 – 1415	Indicates Defect Location & Size. The Report Shall Also Include Discontinuity
	Characterization (Size & Position of Defects in Relation to a Known Datum/s)
	& Evaluation, Echo Dynamic Characterization. The Report Shall Include
	Detection of Mandatory Discontinuities.
1415 - 1430	Break
	Specific Practical Examination (2 hours)
	(D) Develop an NDT Instruction Suitable for a Level 1 Operator for One of the
	Sample Given for Paragraph (B) Above to a Provided Code or Specification. The
1430 -1630	Instruction Shall Detail the Methods of Scanning, File Structure, Collecting &
1450 -1050	Storing Data & The Necessary Calculations to Achieve this. The Instruction
	Shall Include Scope, Status, Authorization, Personnel, Apparatus & Settings,
	Product & Test Area, Test Conditions, Preparation for Testing, Application of
	Test Instructions, Recording & Classifying Results & Report the Results.
1630 - 1645	Course Conclusion
1645 – 1700	Presentation of Course Certificates
1700	End of Course



FE0772-10D - Page 11 of 15







Practical Sessions

Practical sessions will be organized during the course for delegates to practice the theory learnt. Delegates will be provided with an opportunity to carryout various testing using the "Doppler Flexcan 16/64", "IIW Type 2 Calibration Block", "ASME Basic Calibration Block", "Couple of Weld Samples", "Single 'V' Plate to Plate Advanced UT Flawed Specimens 15 mm", "6 inches Pipe to Pipe Ultrasonic Test Flawed Specimens" and "Ultrasonic Couplant Powder".



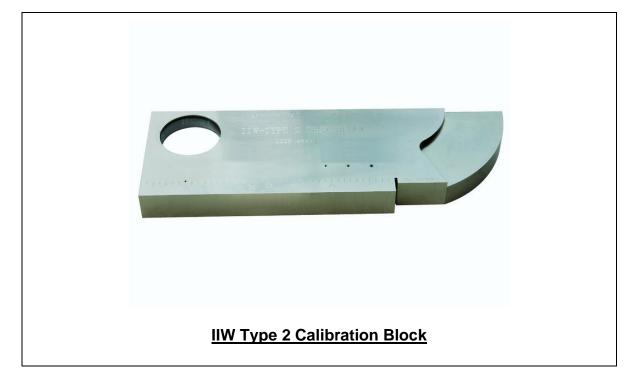


FE0772-10D - Page 12 of 15













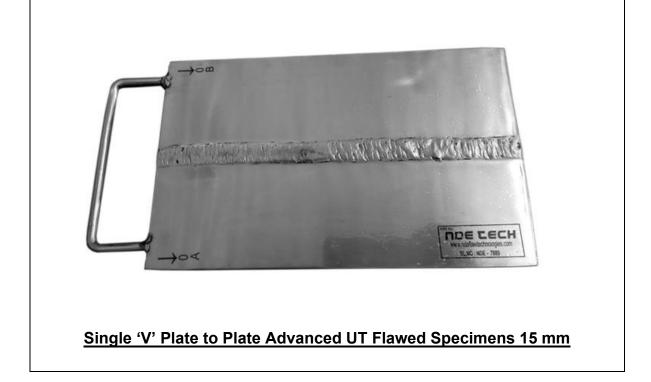
FE0772-10D - Page 13 of 15



🚟 FE0772-10D-04-25|Rev.40|08 November 2024

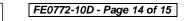










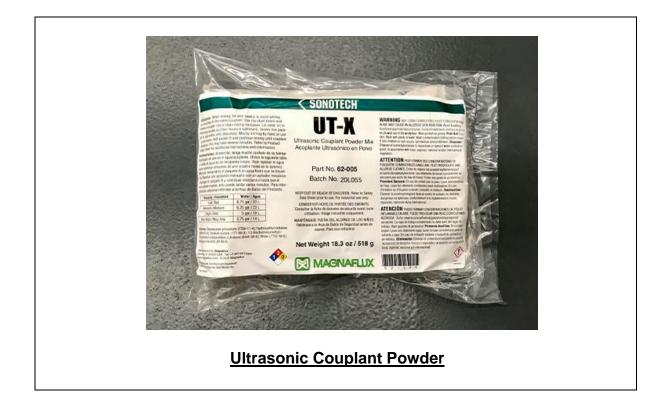




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FE0772-10D - Page 15 of 15

